

DirectFET® N-Channel Power MOSFET

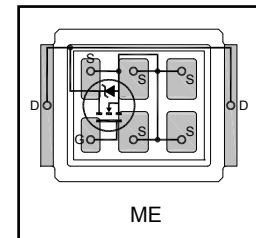
**Application**

- Brushed motor drive applications
- BLDC motor drive applications
- Battery powered circuits
- Half-bridge and full-bridge topologies
- Synchronous rectifier applications
- Resonant mode power supplies
- OR-ing and redundant power switches
- DC/DC and AC/DC converters
- DC/AC inverters

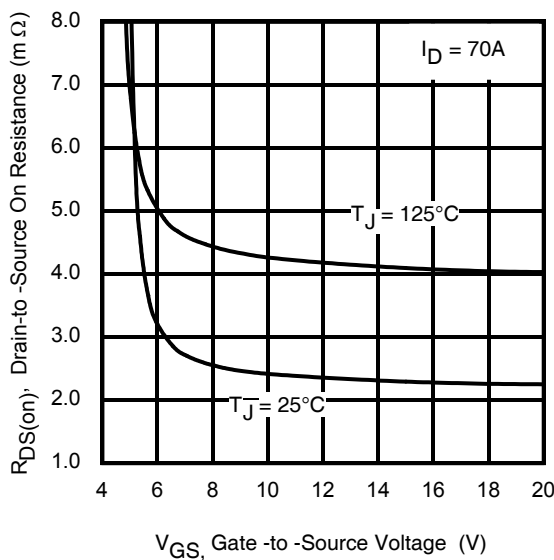
**Benefits**

- Improved gate, avalanche and dynamic dv/dt ruggedness
- Fully characterized capacitance and avalanche SOA
- Enhanced body diode dv/dt and di/dt capability
- Lead-free, RoHS compliant

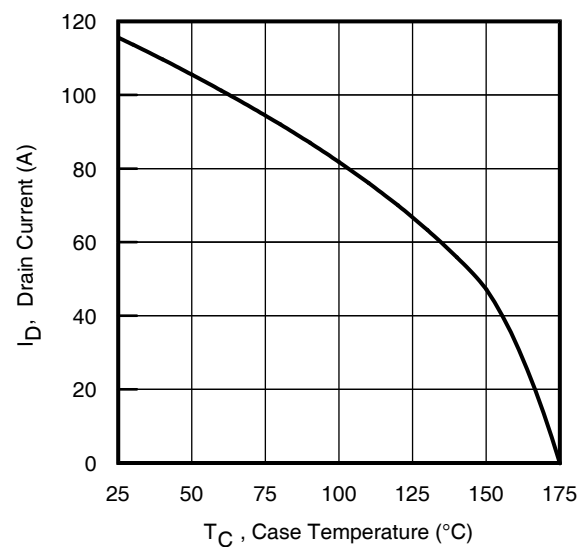
<b>V<sub>DSS</sub></b>	<b>60V</b>
<b>R<sub>DS(on)</sub> typ.</b>	<b>2.9mΩ</b>
	<b>3.6mΩ</b>
<b>I<sub>D</sub></b>	<b>116A</b>



Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRF7580MPbF	DirectFET ME	Tape and Reel	4800	IRF7580MTRPbF



**Fig 1.** Typical On-Resistance vs. Gate Voltage



**Fig 2.** Maximum Drain Current vs. Case Temperature

**Absolute Maximum Ratings**

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	116	A
$I_D @ T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	82	
$I_{DM}$	Pulsed Drain Current ①	460	
$P_D @ T_C = 25^\circ\text{C}$	Maximum Power Dissipation	115	W
	Linear Derating Factor	0.78	W/°C
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 175	°C

**Avalanche Characteristics**

$E_{AS}$ (Thermally limited)	Single Pulse Avalanche Energy ②	100	mJ
$E_{AS}$ (tested)	Single Pulse Avalanche Energy Tested Value ③	120	
$I_{AR}$	Avalanche Current ①	70	A
$E_{AR}$	Repetitive Avalanche Energy ①	12	mJ

**Thermal Resistance**

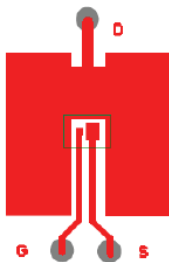
Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient ① ⑦	—	44	°C/W
$R_{\theta JA}$	Junction-to-Ambient ③	12.5	—	
$R_{\theta JA}$	Junction-to-Ambient ②	20	—	
$R_{\theta JC}$	Junction-to-Case ④ ⑧	—	1.3	
$R_{\theta JA-PCB}$	Junction-to-PCB Mounted ②	0.75	—	

**Static @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

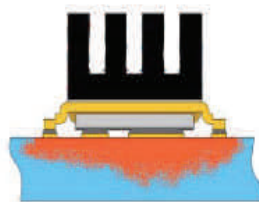
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	60	—	—	V	$V_{GS} = 0\text{V}$ , $I_D = 250\mu\text{A}$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	44	—	mV/°C	Reference to $25^\circ\text{C}$ , $I_D = 1.0\text{mA}$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	2.9	3.6	mΩ	$V_{GS} = 10\text{V}$ , $I_D = 70\text{A}$ ④
		—	3.5	—	mΩ	$V_{GS} = 6.0\text{V}$ , $I_D = 35\text{A}$ ④
$V_{GS(th)}$	Gate Threshold Voltage	2.1	—	3.7	V	$V_{DS} = V_{GS}$ , $I_D = 150\mu\text{A}$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	1.0	μA	$V_{DS} = 60\text{V}$ , $V_{GS} = 0\text{V}$
		—	—	150	μA	$V_{DS} = 60\text{V}$ , $V_{GS} = 0\text{V}$ , $T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100	nA	$V_{GS} = -20\text{V}$
$R_G$	Internal Gate Resistance	—	0.8	—	Ω	

**Notes:**

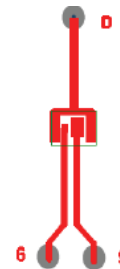
- ② Mounted on minimum footprint full size board with metalized back and with small clip heatsink.
- ③ Used double sided cooling, mounting pad with large heatsink.
- ④ TC measured with thermocouple mounted to top (Drain) of part.



① Surface mounted on 1 in. square Cu board (still air).



② Mounted to a PCB with small clip heatsink (still air)

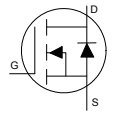


③ Mounted on minimum footprint full size board with metalized back and with small clip heatsink (still air)

**Dynamic @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

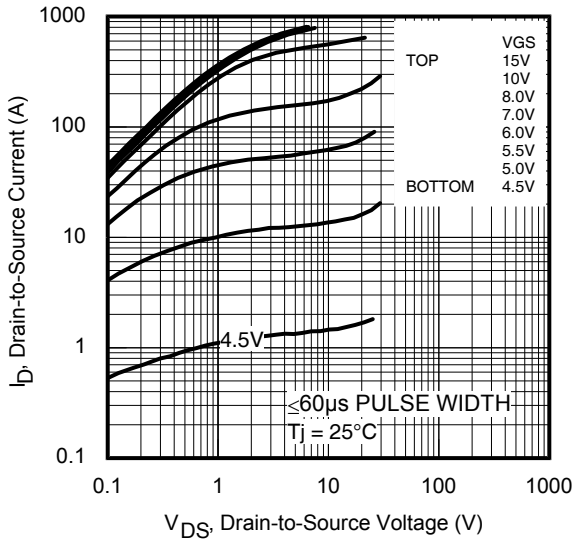
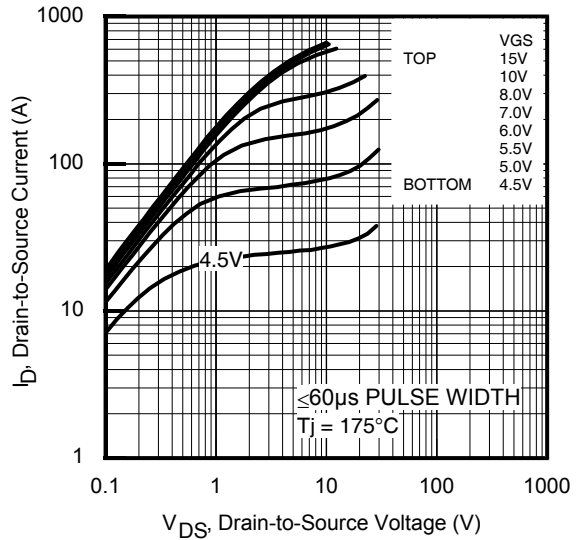
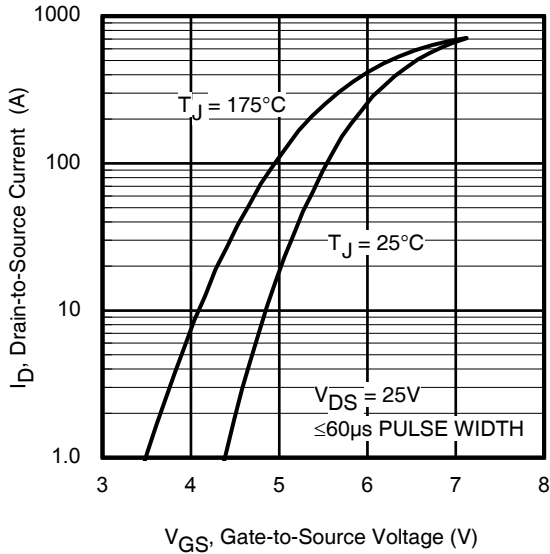
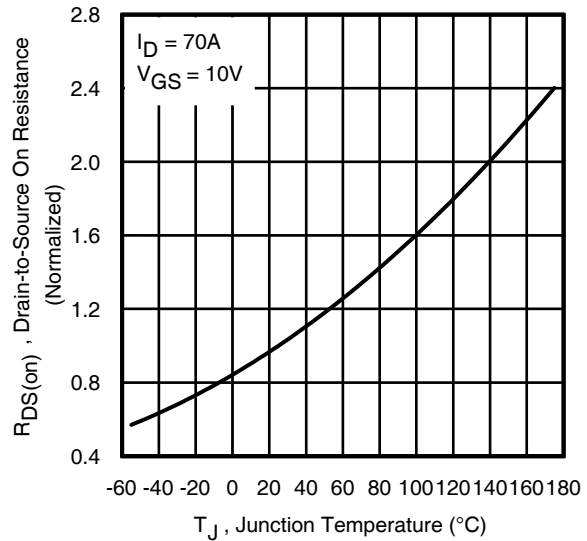
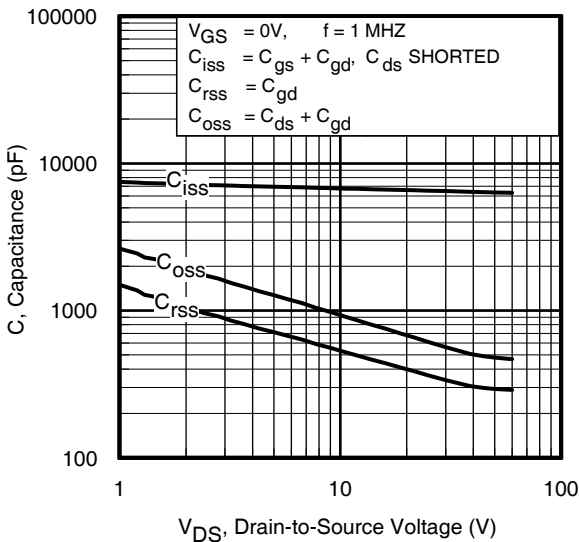
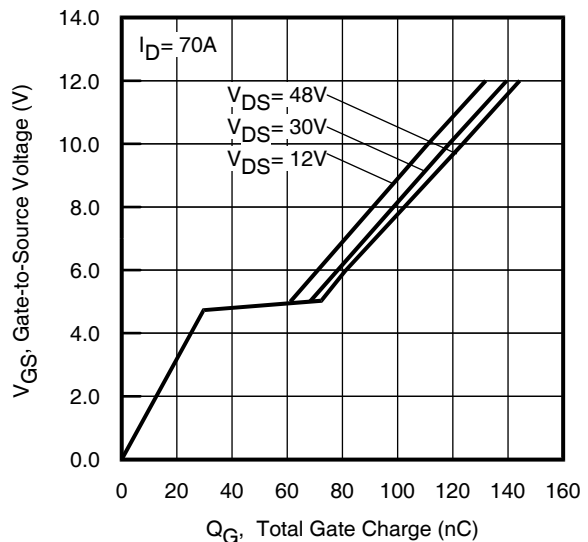
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$g_{fs}$	Forward Transconductance	190	—	—	S	$V_{DS} = 10\text{V}$ , $I_D = 70\text{A}$
$Q_g$	Total Gate Charge	—	120	180	nC	$I_D = 70\text{A}$
$Q_{gs}$	Gate-to-Source Charge	—	32	—		$V_{DS} = 30\text{V}$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	36	—		$V_{GS} = 10\text{V}$ ④
$Q_{sync}$	Total Gate Charge Sync. ( $Q_g - Q_{gd}$ )	—	84	—		$I_D = 70\text{A}$ , $V_{DS} = 0\text{V}$ , $V_{GS} = 10\text{V}$
$t_{d(on)}$	Turn-On Delay Time	—	20	—	ns	$V_{DD} = 30\text{V}$
$t_r$	Rise Time	—	38	—		$I_D = 30\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	53	—		$R_G = 2.7\Omega$
$t_f$	Fall Time	—	21	—		$V_{GS} = 10\text{V}$ ④
$C_{iss}$	Input Capacitance	—	6510	—	pF	$V_{GS} = 0\text{V}$
$C_{oss}$	Output Capacitance	—	610	—		$V_{DS} = 25\text{V}$
$C_{rss}$	Reverse Transfer Capacitance	—	360	—		$f = 1.0\text{MHz}$
$C_{oss}$ eff. (ER)	Effective Output Capacitance (Energy Related)	—	620	—		$V_{GS} = 0\text{V}$ , $V_{DS} = 0\text{V}$ to $48\text{V}$ ⑥
$C_{oss}$ eff. (TR)	Effective Output Capacitance (Time Related)	—	770	—		$V_{GS} = 0\text{V}$ , $V_{DS} = 0\text{V}$ to $48\text{V}$ ⑤

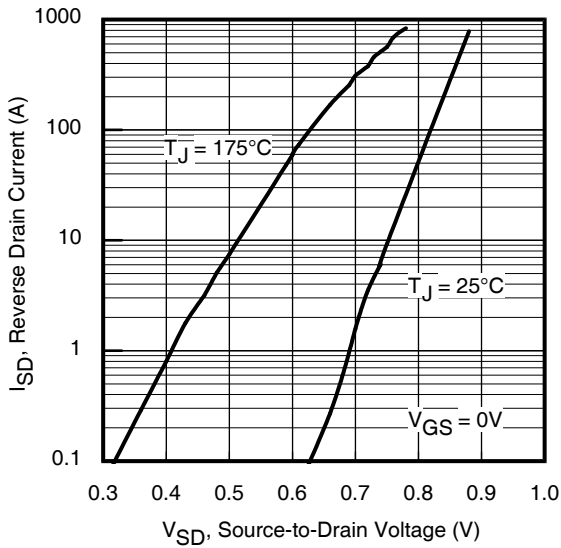
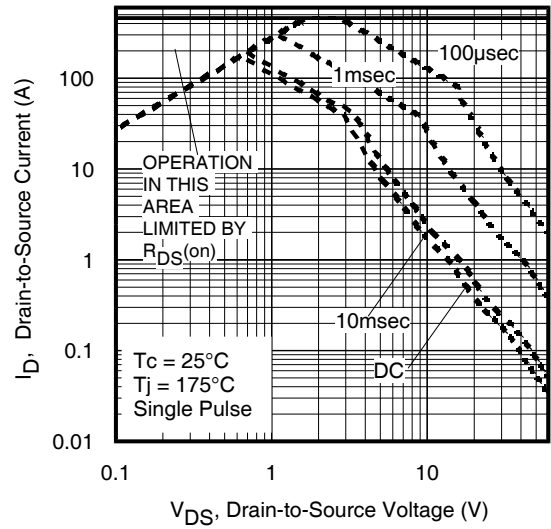
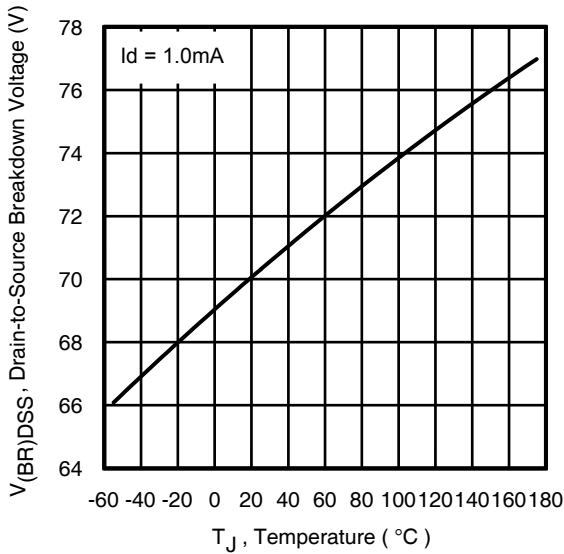
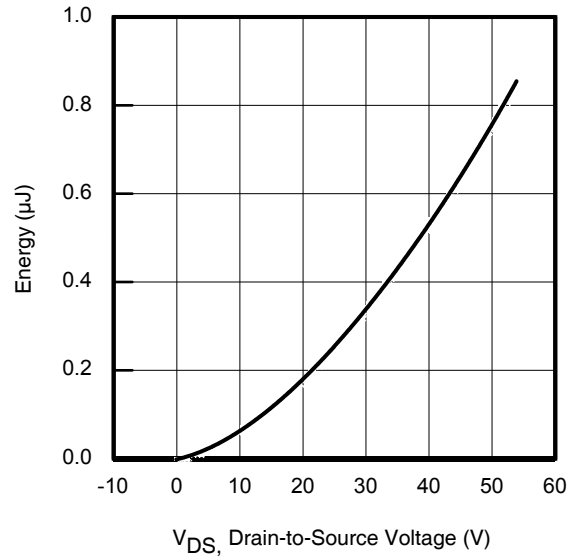
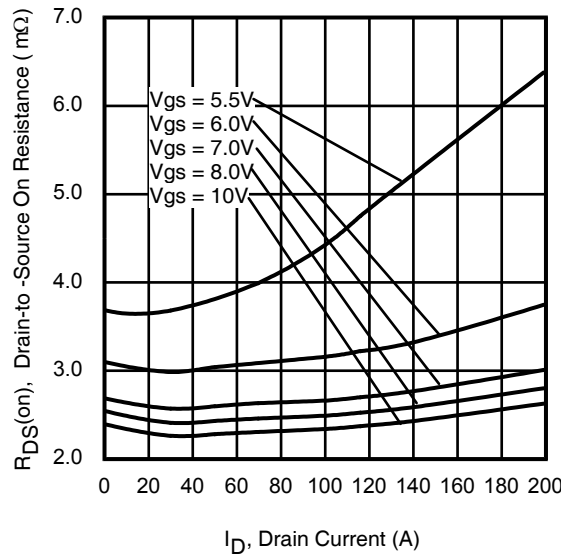
**Diode Characteristics**

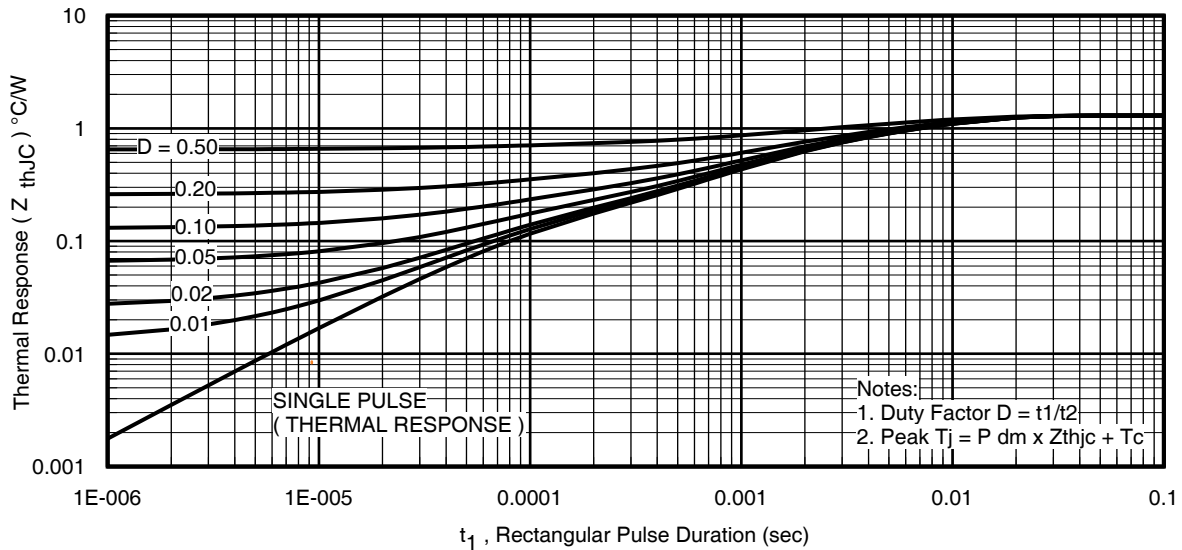
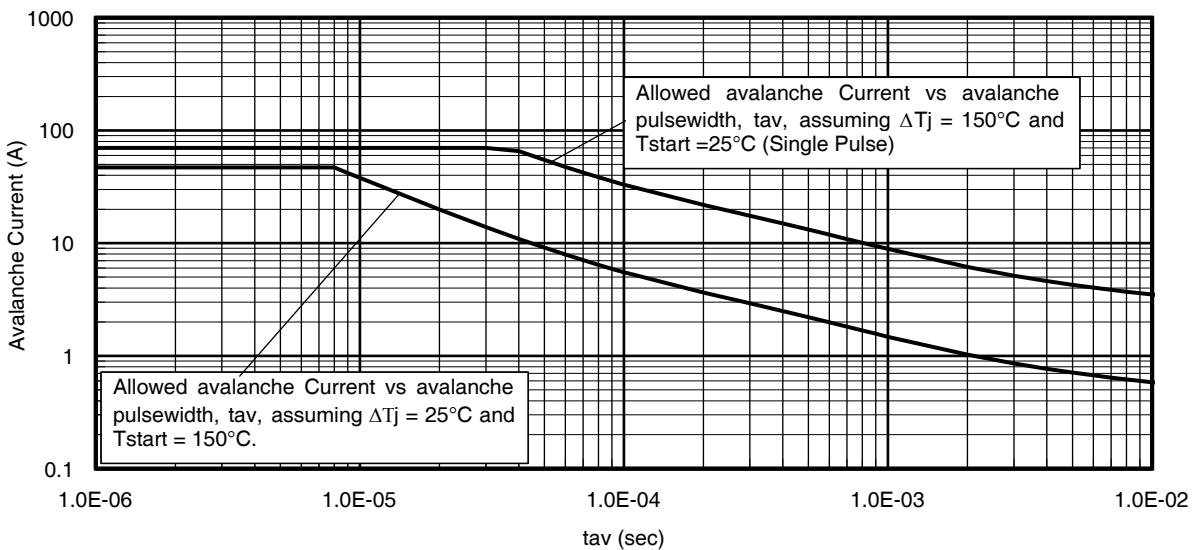
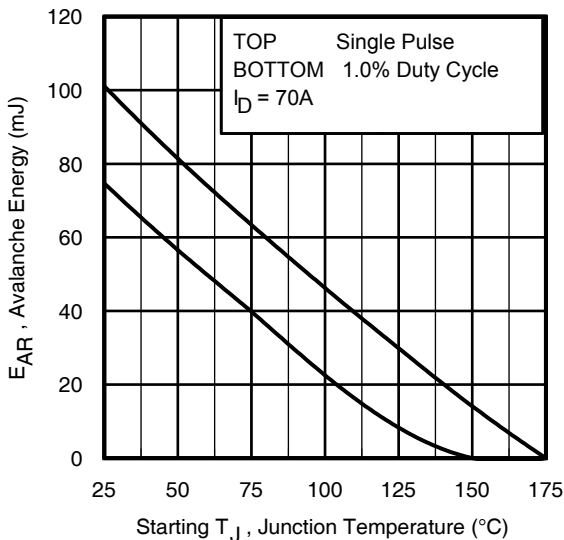
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	105	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	460		
$V_{SD}$	Diode Forward Voltage	—	—	1.2	V	$T_J = 25^\circ\text{C}$ , $I_S = 70\text{A}$ , $V_{GS} = 0\text{V}$ ④
$dv/dt$	Peak Diode Recovery ③	—	4.1	—	V/ns	$T_J = 175^\circ\text{C}$ , $I_S = 70\text{A}$ , $V_{DS} = 60\text{V}$
$t_{rr}$	Reverse Recovery Time	—	41	—	ns	$T_J = 25^\circ\text{C}$ $V_R = 51\text{V}$ ,
		—	44	—		$T_J = 125^\circ\text{C}$ $I_F = 70\text{A}$
$Q_{rr}$	Reverse Recovery Charge	—	55	—	nC	$T_J = 25^\circ\text{C}$ $di/dt = 100\text{A}/\mu\text{s}$ ④
		—	71	—		$T_J = 125^\circ\text{C}$
$I_{RRM}$	Reverse Recovery Current	—	2.5	—	A	$T_J = 25^\circ\text{C}$

**Notes:**

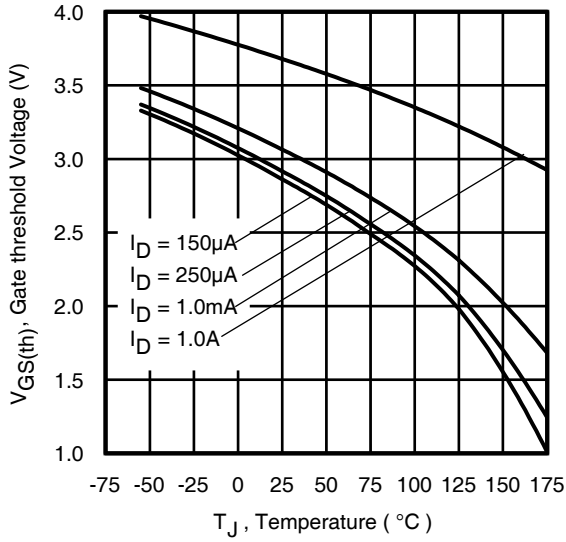
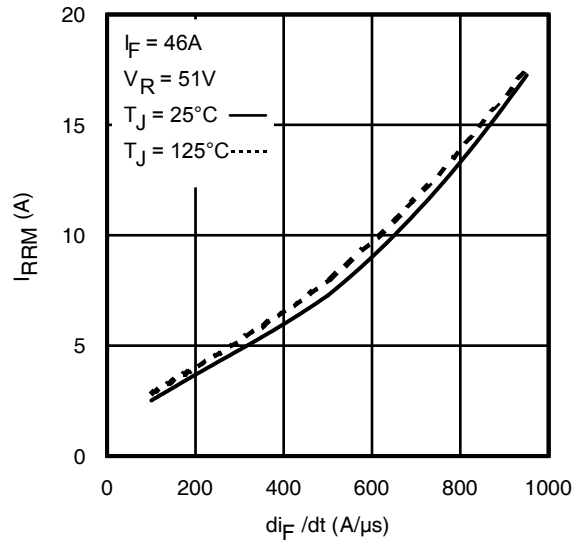
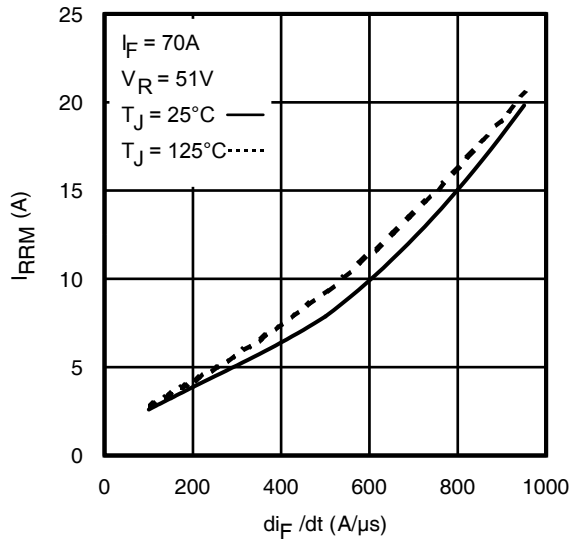
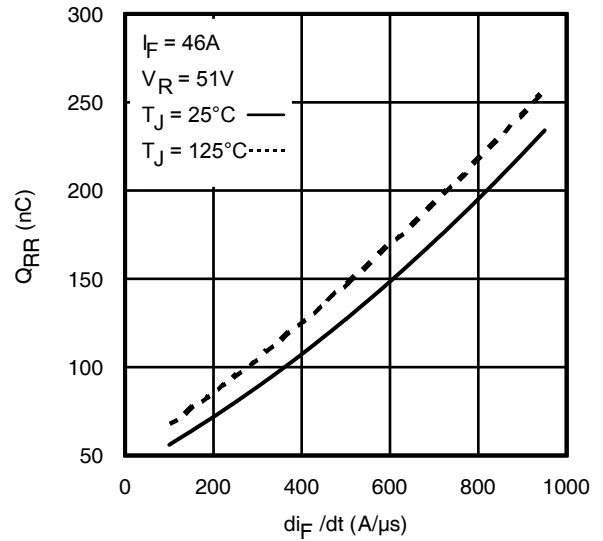
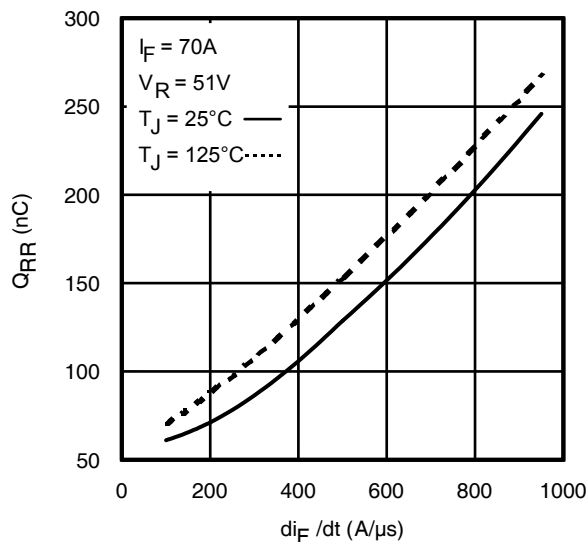
- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25^\circ\text{C}$ ,  $L = 42\mu\text{H}$   
 $R_G = 50\Omega$ ,  $I_{AS} = 70\text{A}$ ,  $V_{GS} = 10\text{V}$ .
- ③  $I_{SD} \leq 70\text{A}$ ,  $di/dt \leq 980\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq 175^\circ\text{C}$ .
- ④ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ⑤  $C_{oss}$  eff. (TR) is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to  $80\% V_{DSS}$ .
- ⑥  $C_{oss}$  eff. (ER) is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to  $80\% V_{DSS}$ .
- ⑦ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- ⑧  $R_\theta$  is measured at  $T_J$  approximately  $90^\circ\text{C}$ .
- ⑨ This value determined from sample failure population, starting  $T_J = 25^\circ\text{C}$ ,  $L = 42\mu\text{H}$ ,  $R_G = 50\Omega$ ,  $I_{AS} = 70\text{A}$ ,  $V_{GS} = 10\text{V}$ .

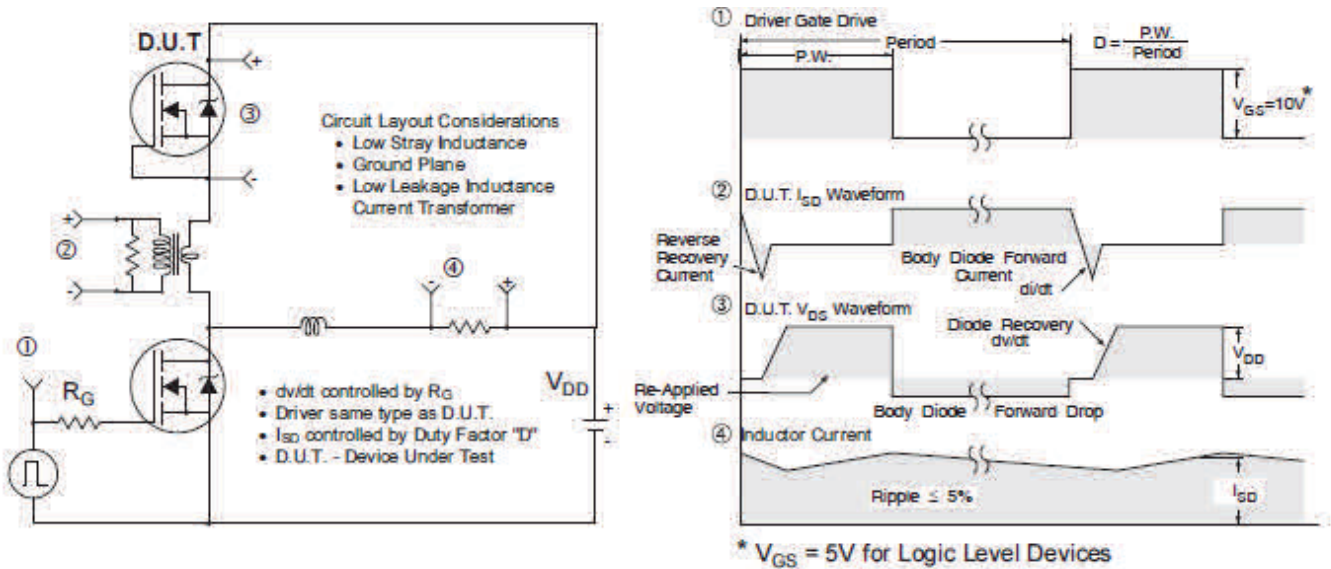

**Fig 3. Typical Output Characteristics**

**Fig 4. Typical Output Characteristics**

**Fig 5. Typical Transfer Characteristics**

**Fig 6. Normalized On-Resistance vs. Temperature**

**Fig 7. Typical Capacitance vs. Drain-to-Source Voltage**

**Fig 8. Typical Gate Charge vs. Gate-to-Source Voltage**


**Fig 9.** Typical Source-Drain Diode Forward Voltage

**Fig 10.** Maximum Safe Operating Area

**Fig 11.** Drain-to-Source Breakdown Voltage

**Fig 12.** Typical  $C_{oss}$  Stored Energy

**Fig 13.** Typical On-Resistance vs. Drain Current

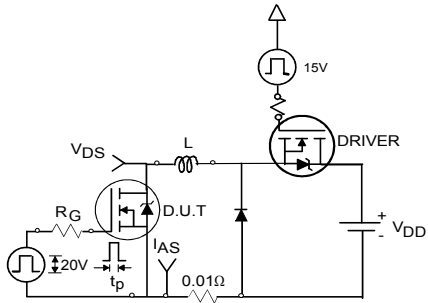

**Fig 14. Maximum Effective Transient Thermal Impedance, Junction-to-Case**

**Fig 15. Avalanche Current vs. Pulse Width**

**Fig 16. Maximum Avalanche Energy vs. Temperature**
**Notes on Repetitive Avalanche Curves , Figures 15, 16:  
(For further info, see AN-1005 at www.irf.com)**

1. Avalanche failures assumption:  
Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 23a, 23b.
4.  $P_{D(ave)}$  = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6.  $I_{av}$  = Allowable avalanche current.
7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 15, 16).  
 $t_{av}$  = Average time in avalanche.  
 $D$  = Duty cycle in avalanche =  $t_{av} \cdot f$   
 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)  
 $P_{D(ave)} = 1/2 ( 1.3 \cdot BV \cdot I_{av} ) = \Delta T / Z_{thJC}$   
 $I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$   
 $E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$

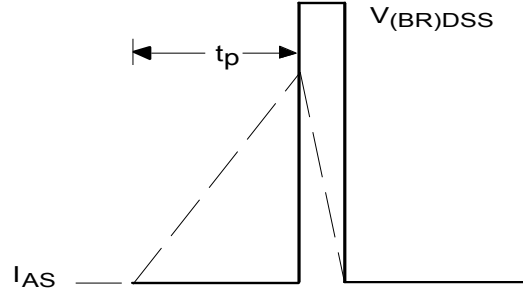

**Fig 17.** Threshold Voltage vs. Temperature

**Fig 18.** Typical Recovery Current vs.  $di/dt$ 

**Fig 19.** Typical Recovery Current vs.  $di/dt$ 

**Fig 20.** Typical Stored Charge vs.  $di/dt$ 

**Fig 21.** Typical Stored Charge vs.  $di/dt$



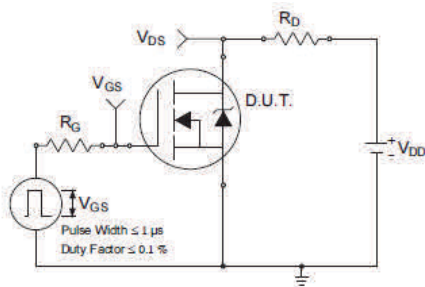
**Fig 22.** Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs



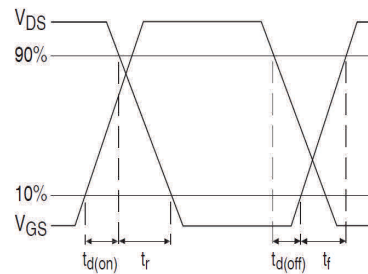
**Fig 23a.** Unclamped Inductive Test Circuit



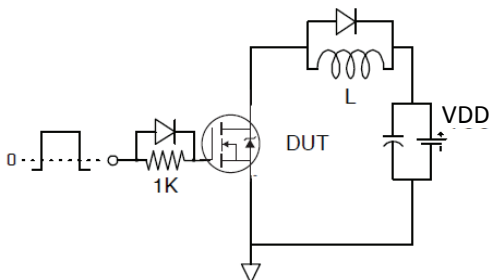
**Fig 23b.** Unclamped Inductive Waveforms



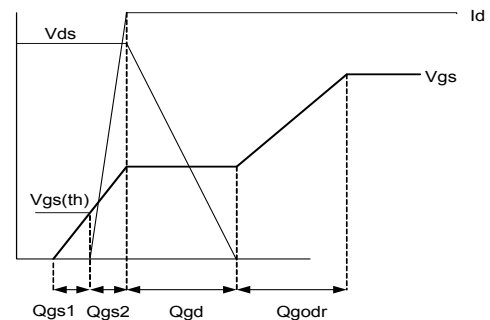
**Fig 24a.** Switching Time Test Circuit



**Fig 24b.** Switching Time Waveforms



**Fig 25a.** Gate Charge Test Circuit

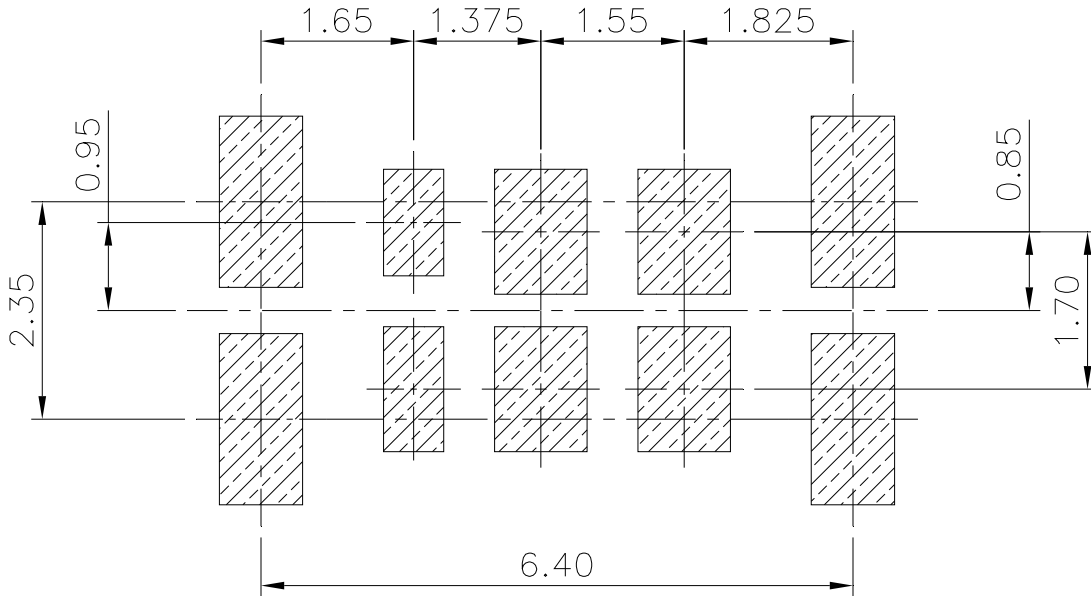


**Fig 25b.** Gate Charge Waveform

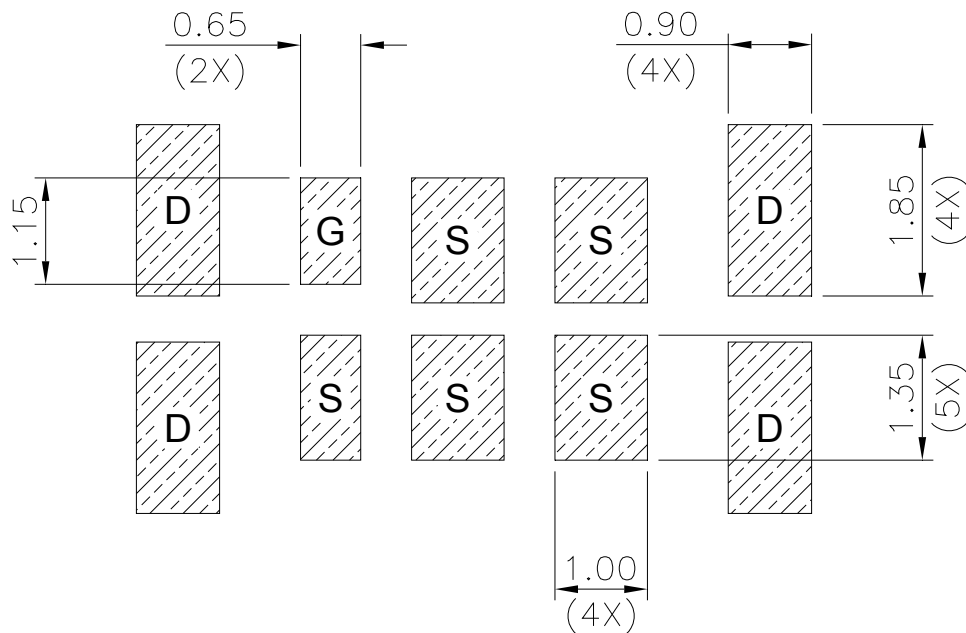


**DirectFET® Board Footprint, ME Outline  
(Medium Size Can, E-Designation)**

Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET. This includes all recommendations for stencil and substrate designs.



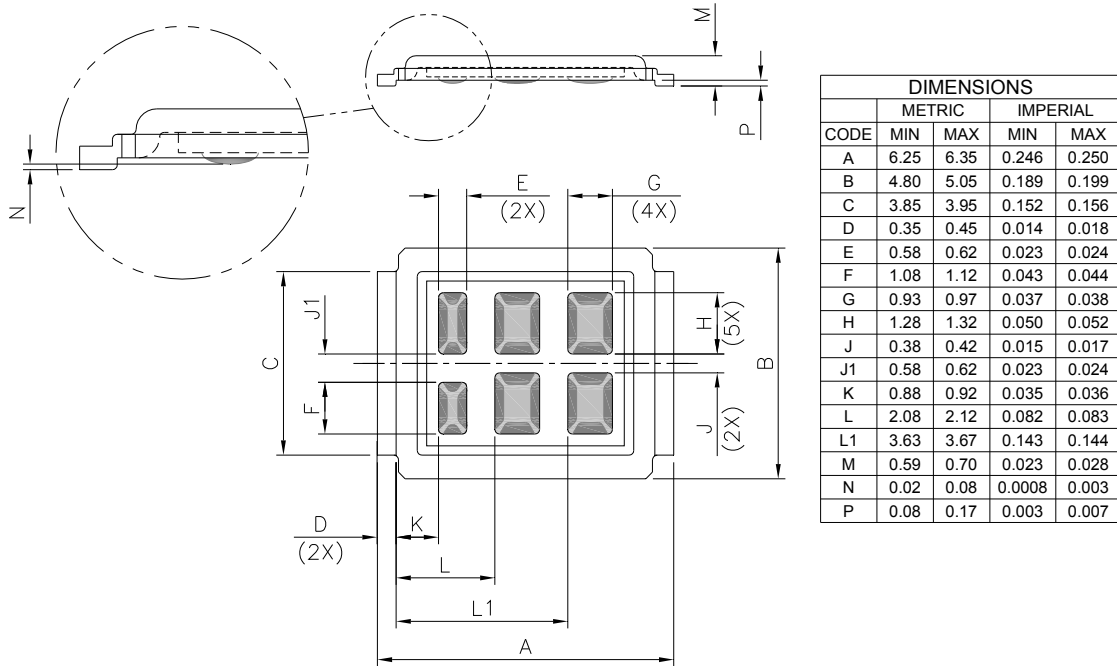
G = GATE  
D = DRAIN  
S = SOURCE



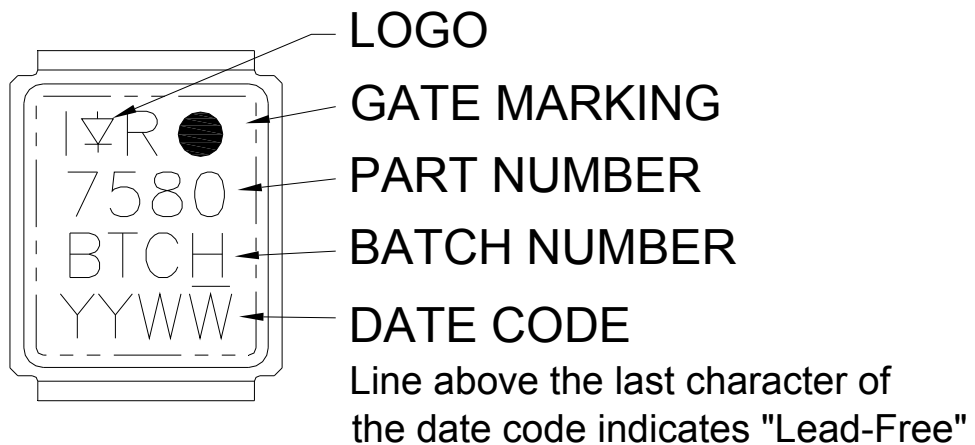
Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**DirectFET® Outline Dimension, ME Outline  
(Medium Size Can, E-Designation)**

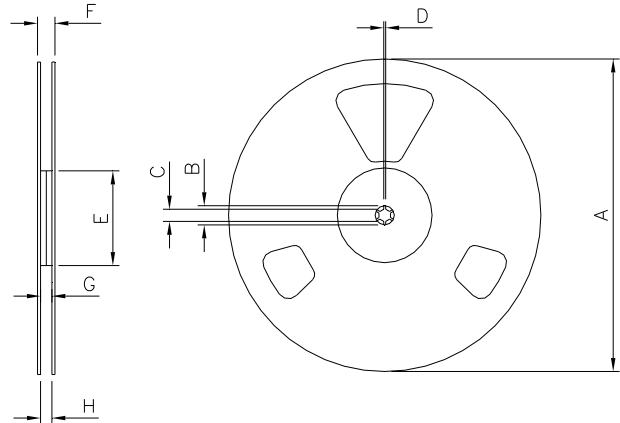
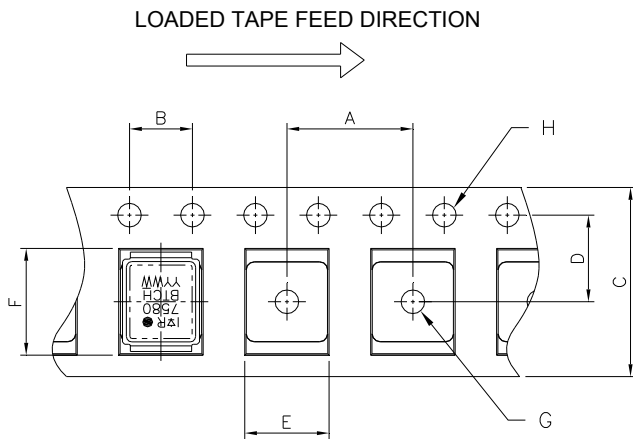
Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET. This includes all recommendations for stencil and substrate designs.



Dimensions are shown in millimeters (inches)

**DirectFET® Part Marking**


Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**DirectFET® Tape & Reel Dimension (Showing component orientation).**


NOTE: Controlling dimensions in mm  
Std reel quantity is 4800 parts. (ordered as IRF7580MTRPbF). For 1000 parts on 7" reel, order IRF7580MTR1PbF

NOTE: CONTROLLING DIMENSIONS IN MM

CODE	DIMENSIONS			
	METRIC		IMPERIAL	
	MIN	MAX	MIN	MAX
A	7.90	8.10	0.311	0.319
B	3.90	4.10	0.154	0.161
C	11.90	12.30	0.469	0.484
D	5.45	5.55	0.215	0.219
E	5.10	5.30	0.201	0.209
F	6.50	6.70	0.256	0.264
G	1.50	N.C	0.059	N.C
H	1.50	1.60	0.059	0.063

REEL DIMENSIONS								
STANDARD OPTION (QTY 4800)					TR1 OPTION (QTY 1000)			
CODE	METRIC		IMPERIAL		METRIC		IMPERIAL	
	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX
A	330.0	N.C	12.992	N.C	177.77	N.C	6.9	N.C
B	20.2	N.C	0.795	N.C	19.06	N.C	0.75	N.C
C	12.8	13.2	0.504	0.520	13.5	12.8	0.53	0.50
D	1.5	N.C	0.059	N.C	1.5	N.C	0.059	N.C
E	100.0	N.C	3.937	N.C	58.72	N.C	2.31	N.C
F	N.C	18.4	N.C	0.724	N.C	13.50	N.C	0.53
G	12.4	14.4	0.488	0.567	11.9	12.01	0.47	N.C
H	11.9	15.4	0.469	0.606	11.9	12.01	0.47	N.C

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**Qualification Information†**

<b>Qualification Level</b>	Industrial (per JEDEC JESD47F <sup>††</sup> guidelines)	
<b>Moisture Sensitivity Level</b>	DFET 1.5	MSL3 (per JEDEC J-STD-020D <sup>††</sup> )
<b>RoHS Compliant</b>	Yes	

† Qualification standards can be found at International Rectifier's web site

<http://www.irf.com/product-info/reliability>

†† Applicable version of JEDEC standard at the time of product release.

\* Industrial qualification standards except autoclave test conditions.